



# Whiskers on Monitor PCBs

September 5, 2008

## Abstract

Two (2) failed monitors were physically examined to assess potential failures. Long metal whiskers ( $> 900$  microns) were observed on USB housings. Failure of monitors not directly linked to tin whiskers.

# Background

- Several failed LCD monitors purchased from Great Lakes Electronics Corp. [www.recycleelectronics.com](http://www.recycleelectronics.com) - a de-manufacturing and recycling company specializing in office computers. Reselling of some hardware is done through ebay: [www.stores.ebay.com/Great-Lakes-Electronics-Corp](http://www.stores.ebay.com/Great-Lakes-Electronics-Corp)
- Malfunction of the monitors was traced to the interruption of an electrical fuse. Replacement of a fuse returned function to normal
- Root cause of the current overload remains undetermined
- Physical examination of USB ports on the monitor video PCBs were found to have tin whiskers present on their surfaces.
- Observed whiskers were long enough to bridge fine pitched perimeter leaded packaged integrated circuits on the PWAs.

# Printed Circuit Boards

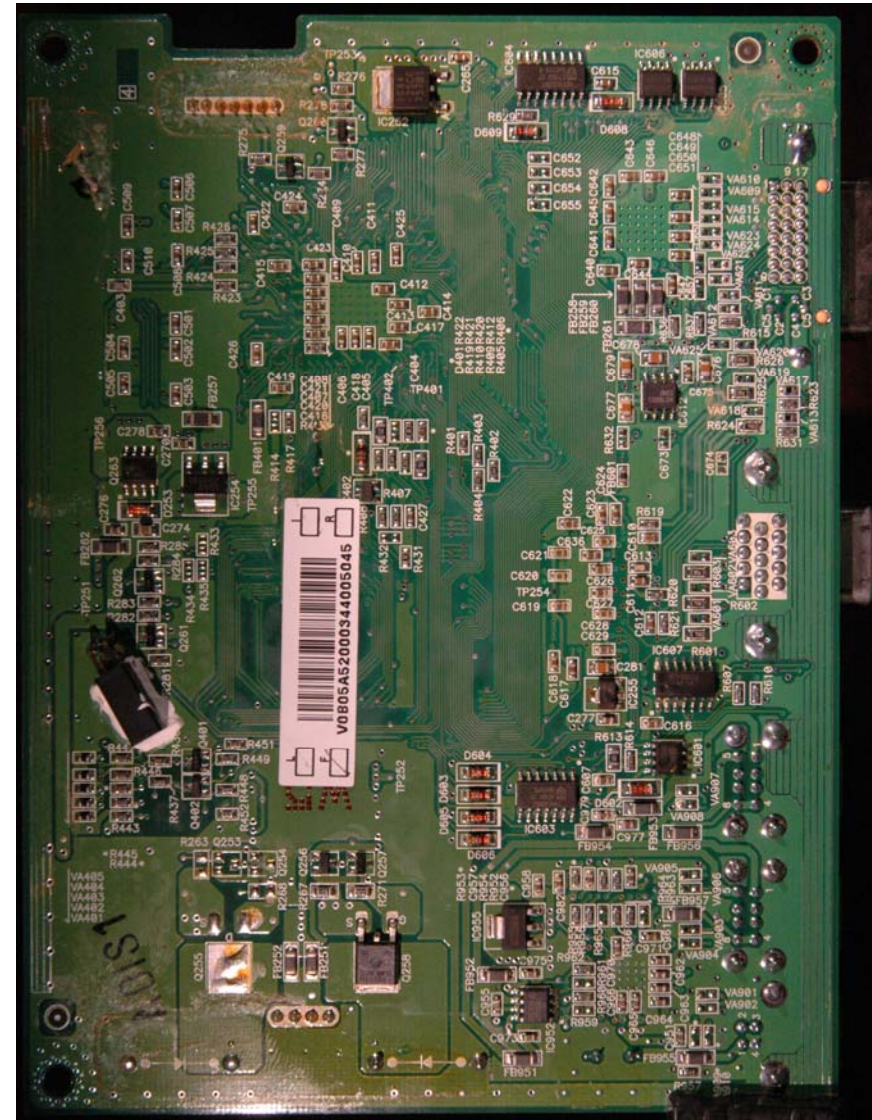
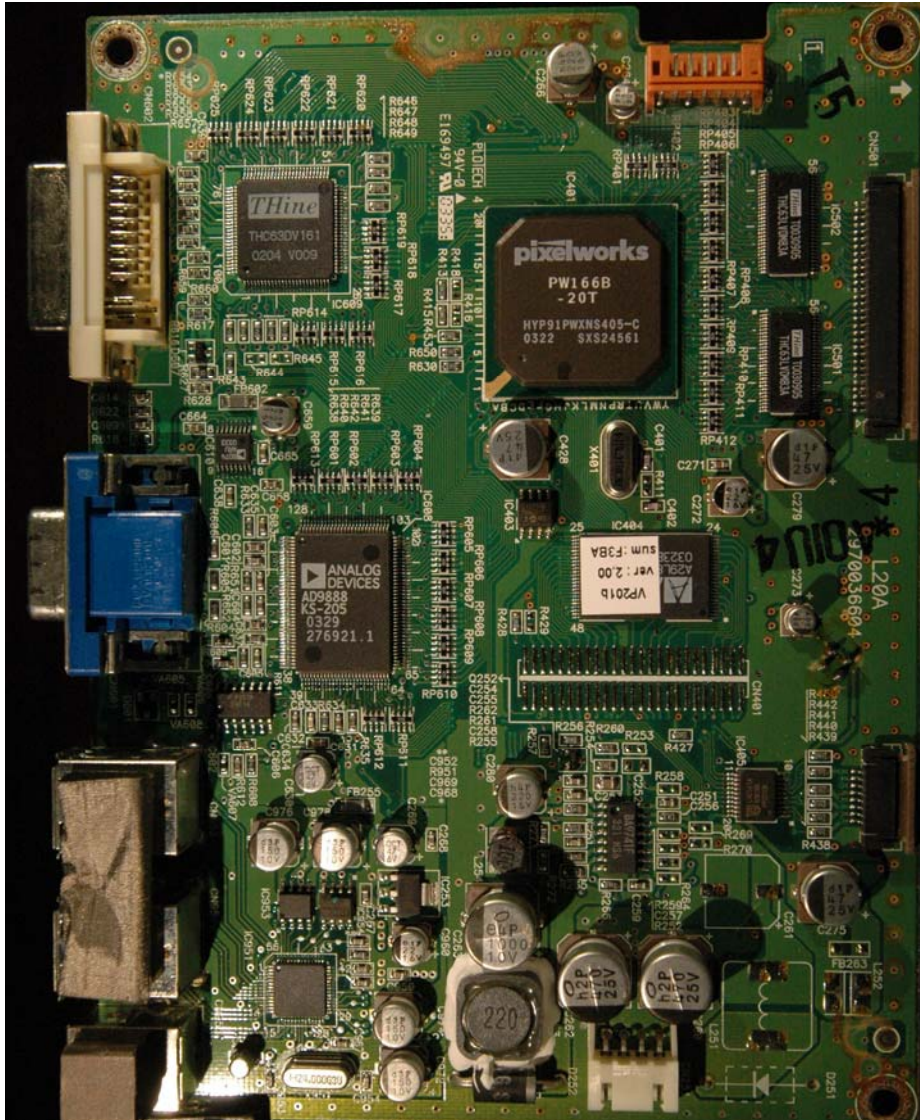
- Both boards labeled by Plotech Co, LTD [www.plotech.com](http://www.plotech.com) – a PCB manufacturer originating in Taiwan, with LCD monitors listed as one of their specialties



- The four digit markings 0335 and 0337 are suspected to be date codes of the form YYWW
- Date codes on some of the components are in mid-2003 year (possibly, the locations of the component manufactures are close to the PCB manufacturing, and a well-established supply exists, resulting in parts not stored for long periods of time)
- Boards contained a variety of electronic parts including relatively fine pitched quad flatpacks, AD9888 and THC63DV161

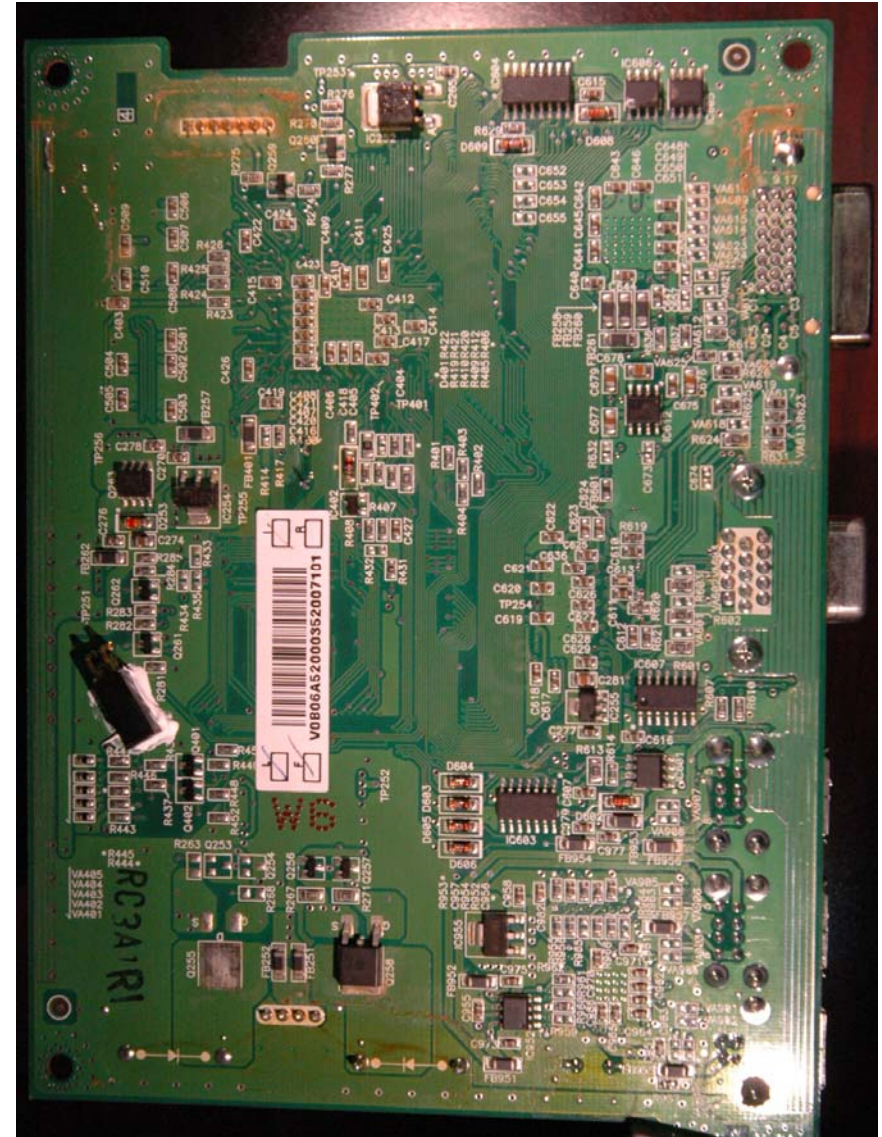
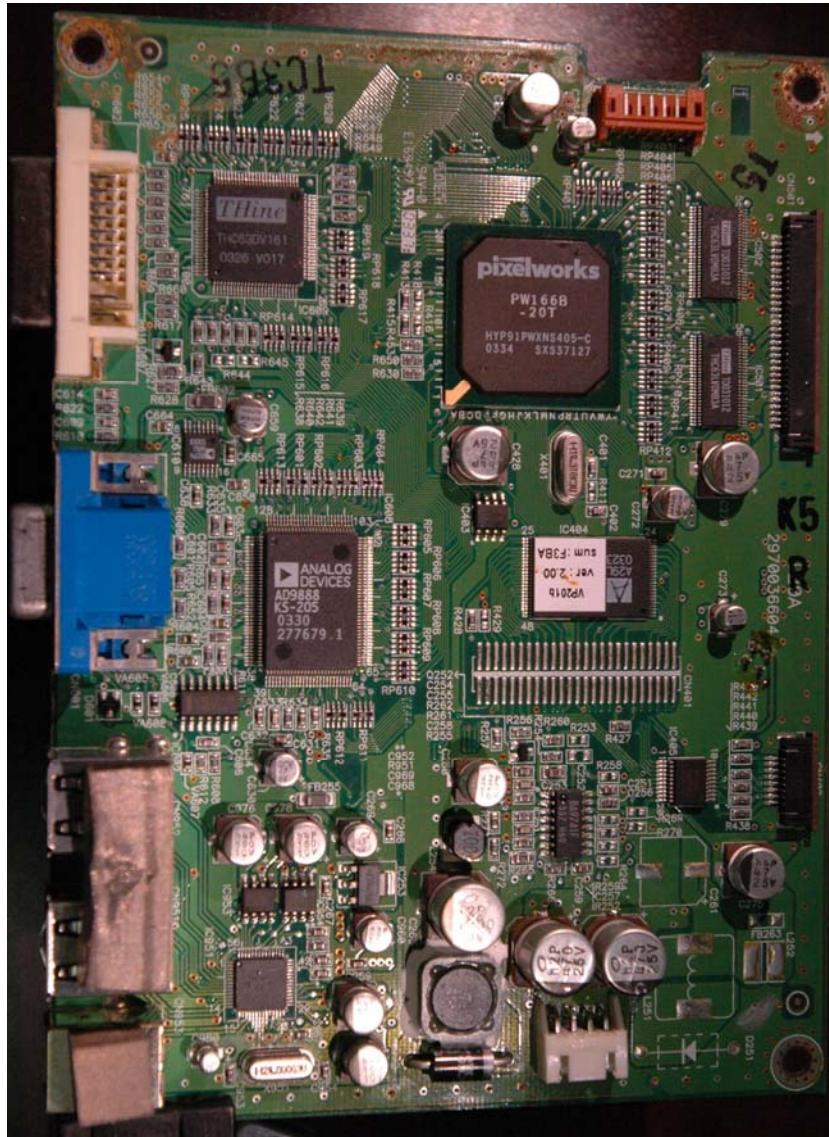


# Video Board 0335 - Overview





# Video Board 0337 - Overview

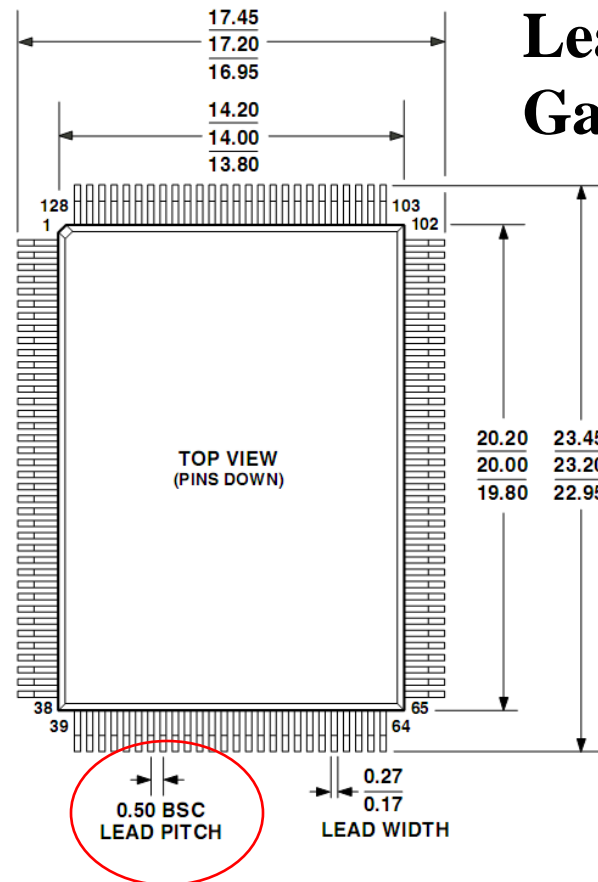


# Components on Board: AD9888

- AD9888: 205 MSPS Highly Integrated Graphics Digitizer for UXGA and HDTV Displays



128-Lead Metric Quad Flat Package [MQFP]  
(S-128-1)  
Dimensions shown in millimeters.

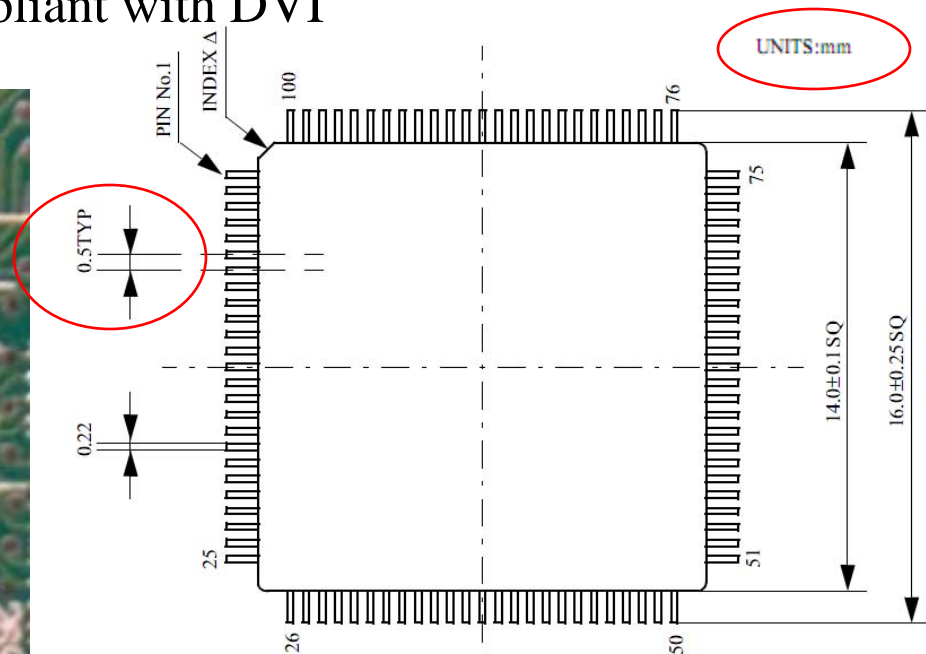


**Pitch: 500 microns**  
**Lead Width: 170-270 microns**  
**Gap: 330-220 microns**



# Components on Board: THC63DV161

- THC63DV161 – a receiver, compliant with DVI



**Pitch: 500 microns**

**Lead Width: 220 microns**

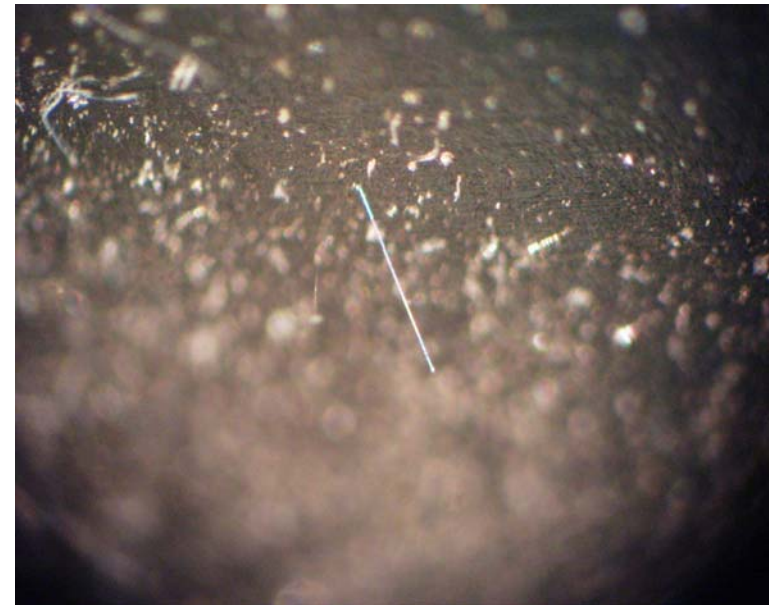
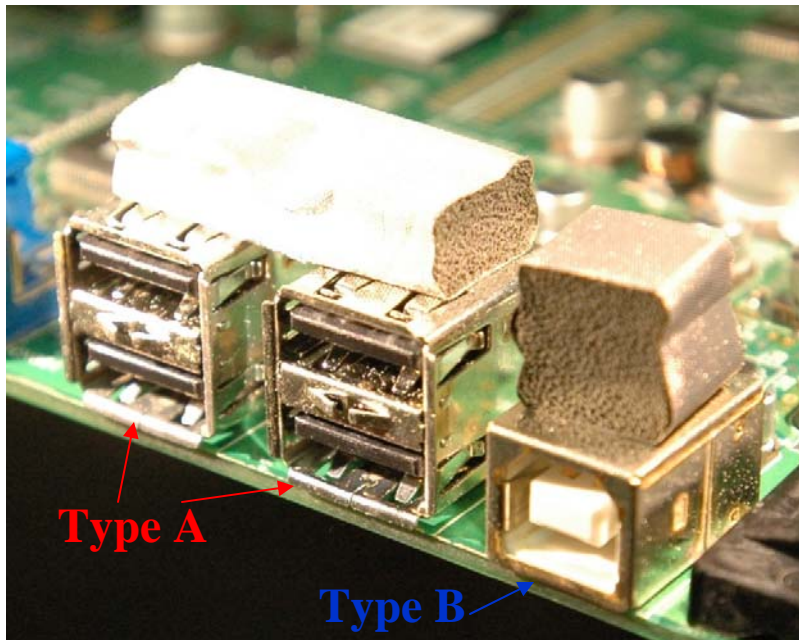
**Gap: 280 microns**

# Observations on the Boards

- Corrosion observed around the perimeter of the PCB and in some vias



- Five USB ports: four of type “A” and one of type “B” – all unmarked
  - Whiskers found on the metal housings of the ports



**Example of a whisker on board 0335  
(USB A) under optical microscope**

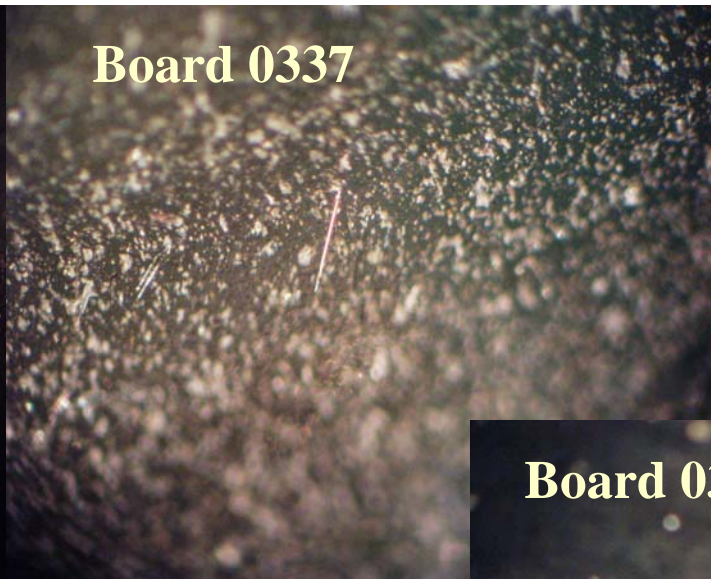
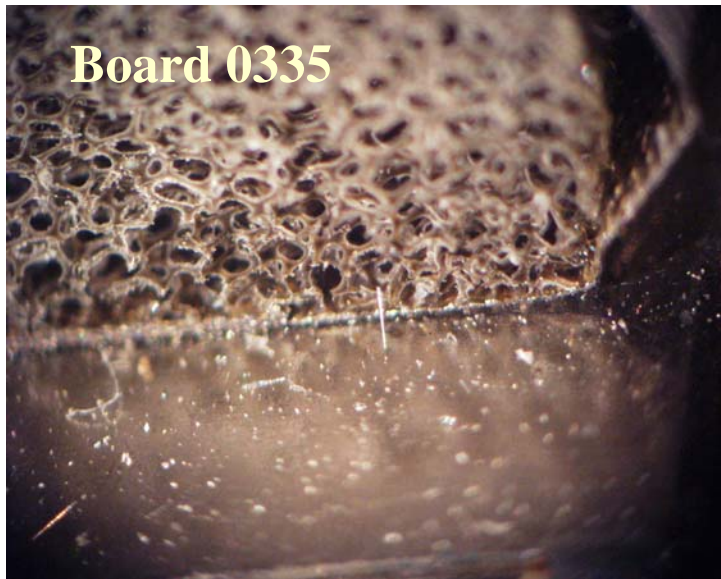


# Corrosion

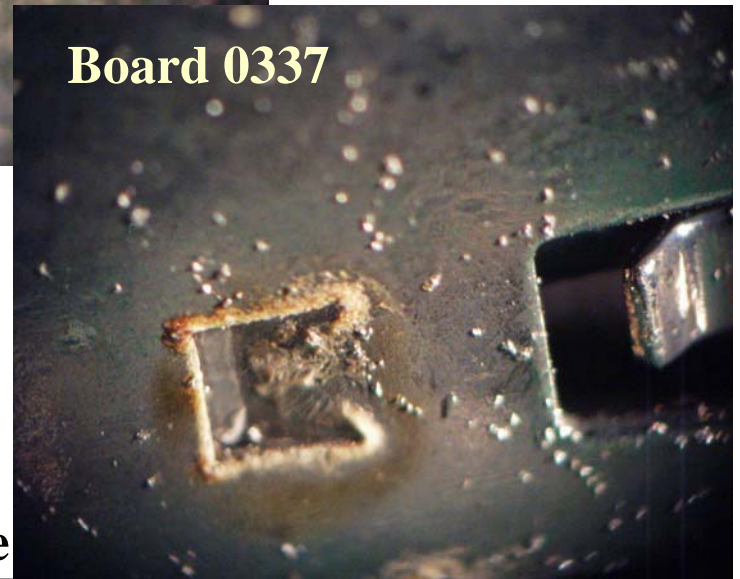
- Environment of the monitor in the prior 5 years is unknown
- Corrosion observed around the edges of the PCB may have been induced by the galvanic cell made up of the PCB and the frame it was mounted on
- Material analysis of the frame showed it to be Zn-coated Fe (Zn  $\sim 2.5\mu\text{m}$  thick)
- Optical inspection of the frame did not reveal presence of zinc whiskers
- Screws that mounted PCB on the frame are Fe-base with Zn coating, with Cr finish (Zn  $\sim 2\mu\text{m}$ , Cr  $< 1\mu\text{m}$ ) *[although the material composition is correct, thicknesses and order of layers may be wrong – XRF analysis leaves those for guessing. The outsides of the screw are yellow-hue]*
- The PCB material is suspected to be FR-4 material based on company's website

# Whisker Observations

- Optical observations for whiskers and nodules made on both assembled boards
- Later, USB connectors were de-soldered for closer observation



**Long Filament-type whiskers**



**Nodules on the surface**

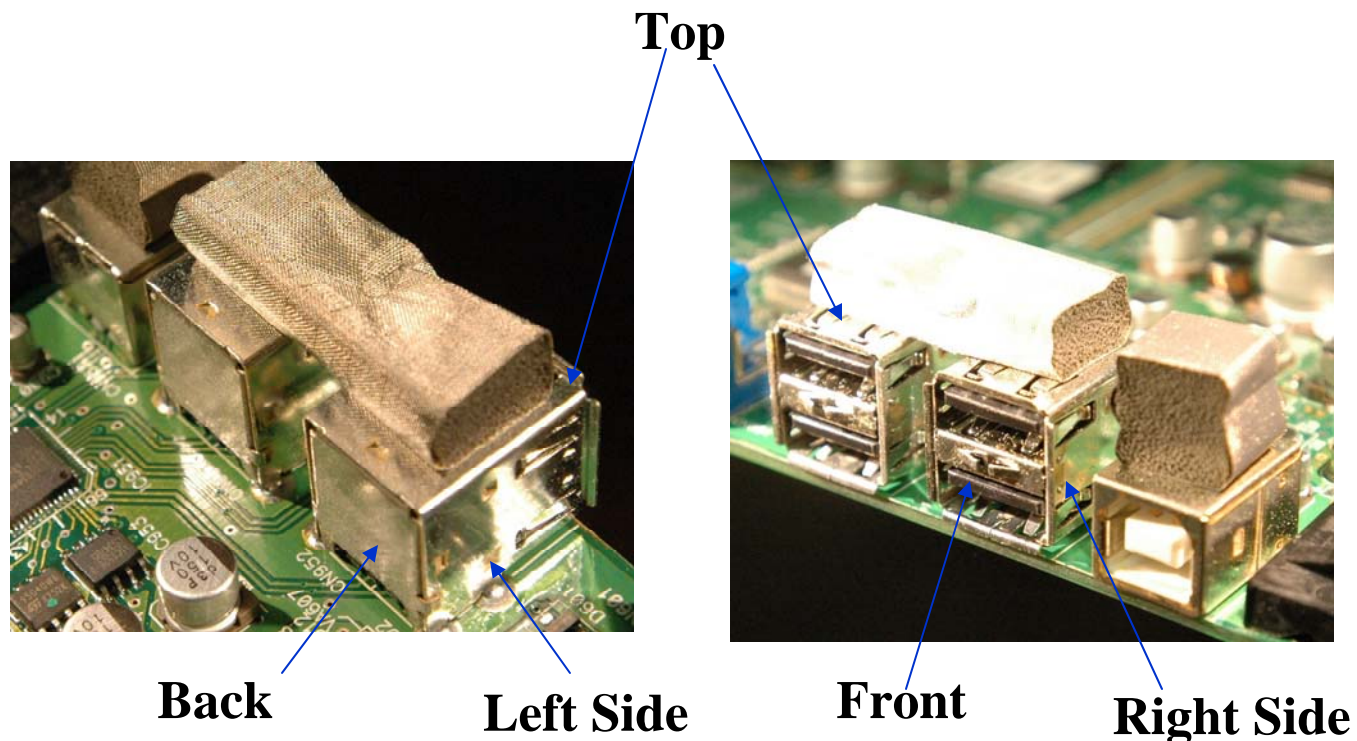
# Material Analysis of the Connectors

- Material analysis of the connectors showed presence of Zn, Cu and Sn
- Assumed a Zn-Cu base (brass) plated with Sn
- Sn has measured to be  $\sim 5\mu\text{m}$  thick
- Although any Sn surface has the potential to grow whiskers, Sn in 2-10 $\mu\text{m}$  thickness has been reportedly cited as more whisker-prone
- Brass reported as a good whisker-prone base material under Sn plating

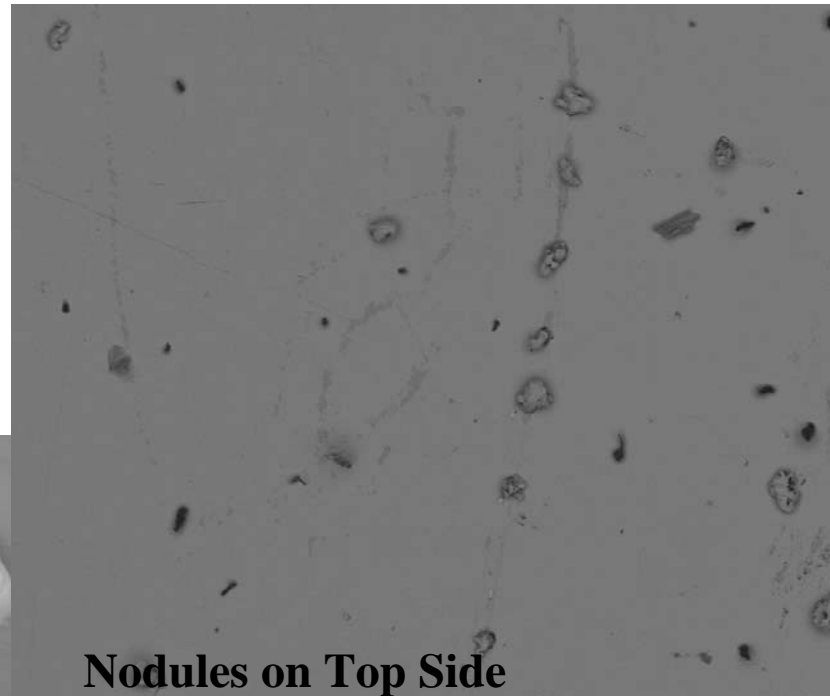


# Looking for Whiskers

- Upon de-soldering and foam removal, 3 USB connectors observed:
  - USB type “A” from board 0335 (mostly nodulation, some whiskers  $300\mu\text{m}$ )
  - USB type “B” from board 0337 (lots of nodulation, whiskers  $>500\mu\text{m}$ )
- Observations made on top, front, two sides, and back of each connector



# Board 0335 – USB “A” #1



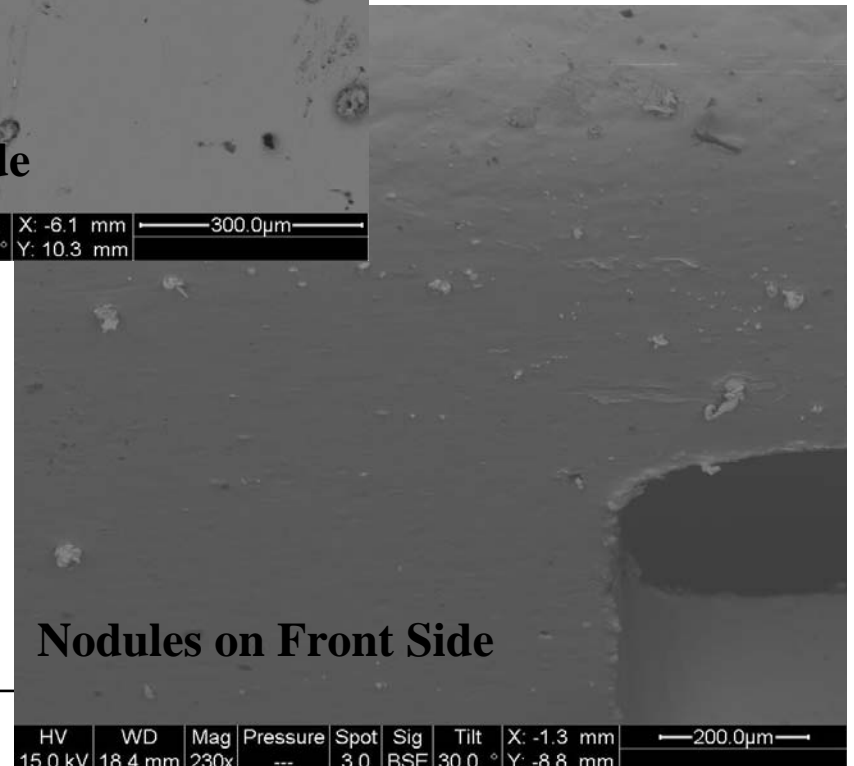
**Nodules on Top Side**

HV	WD	Mag	Pressure	Spot	Sig	Tilt	X: -6.1 mm	Y: 10.3 mm	300.0μm
15.0 kV	11.0 mm	230x	---	3.0	BSE	0.0 °			



**Whisker on Left Side**

HV	WD	Mag	Pressure	Spot	Sig	Tilt	X: 2.3 mm	Y: -13.7 mm	50.0μm
15.0 kV	21.8 mm	903x	---	3.0	BSE	30.0 °			



**Nodules on Front Side**

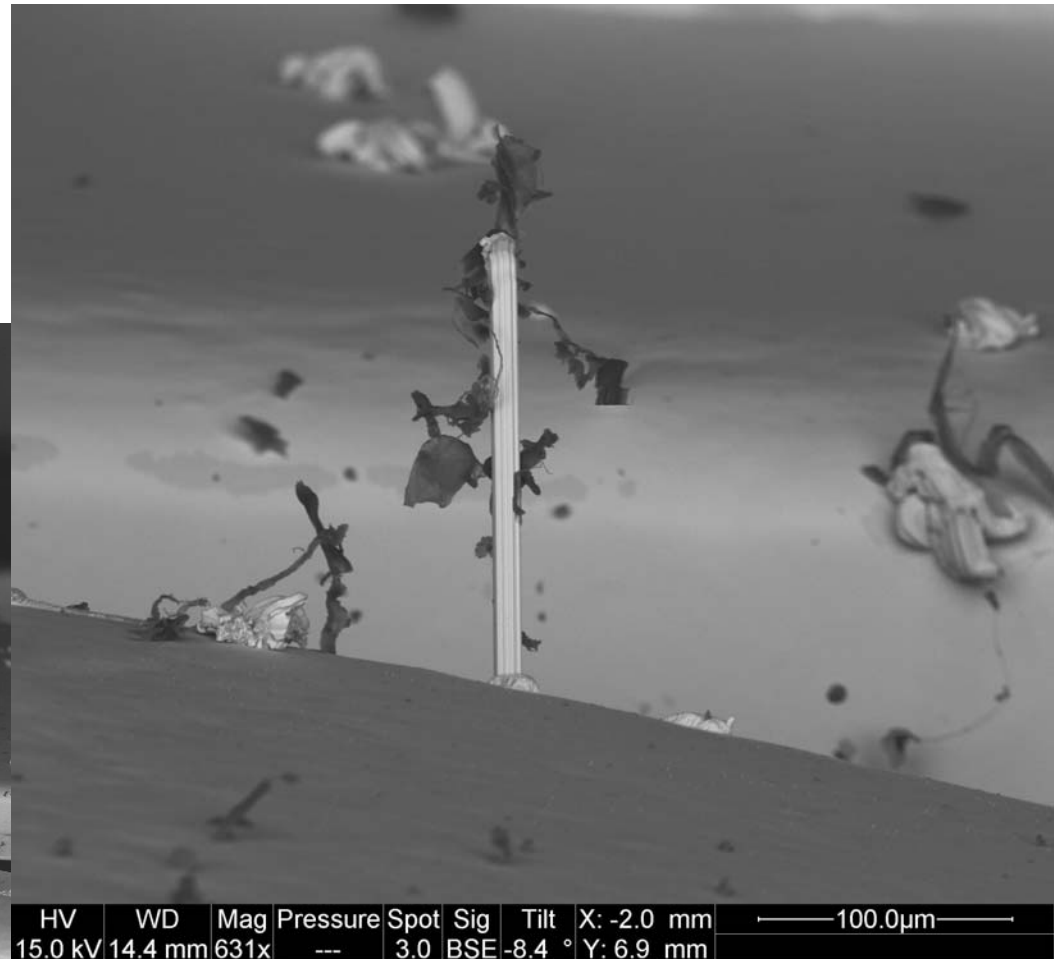
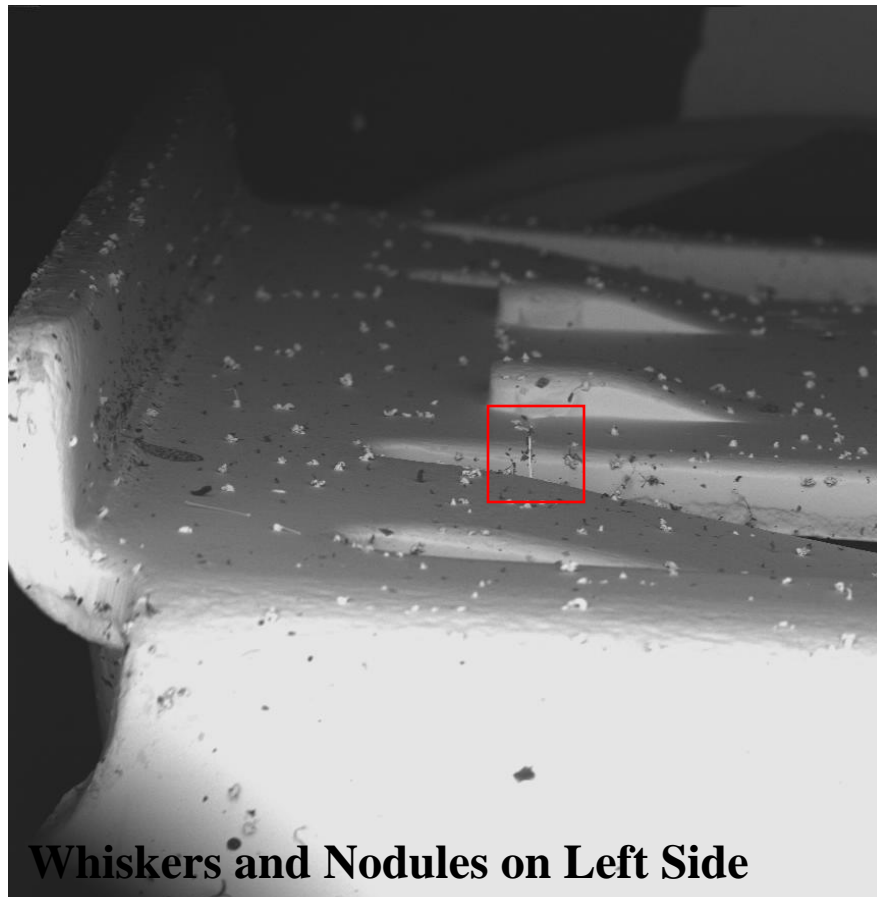
HV	WD	Mag	Pressure	Spot	Sig	Tilt	X: -1.3 mm	Y: -8.8 mm	200.0μm
15.0 kV	18.4 mm	230x	---	3.0	BSE	30.0 °			

# Board 0335 – USB “A” #2





# Board 0335 – USB “A” #2

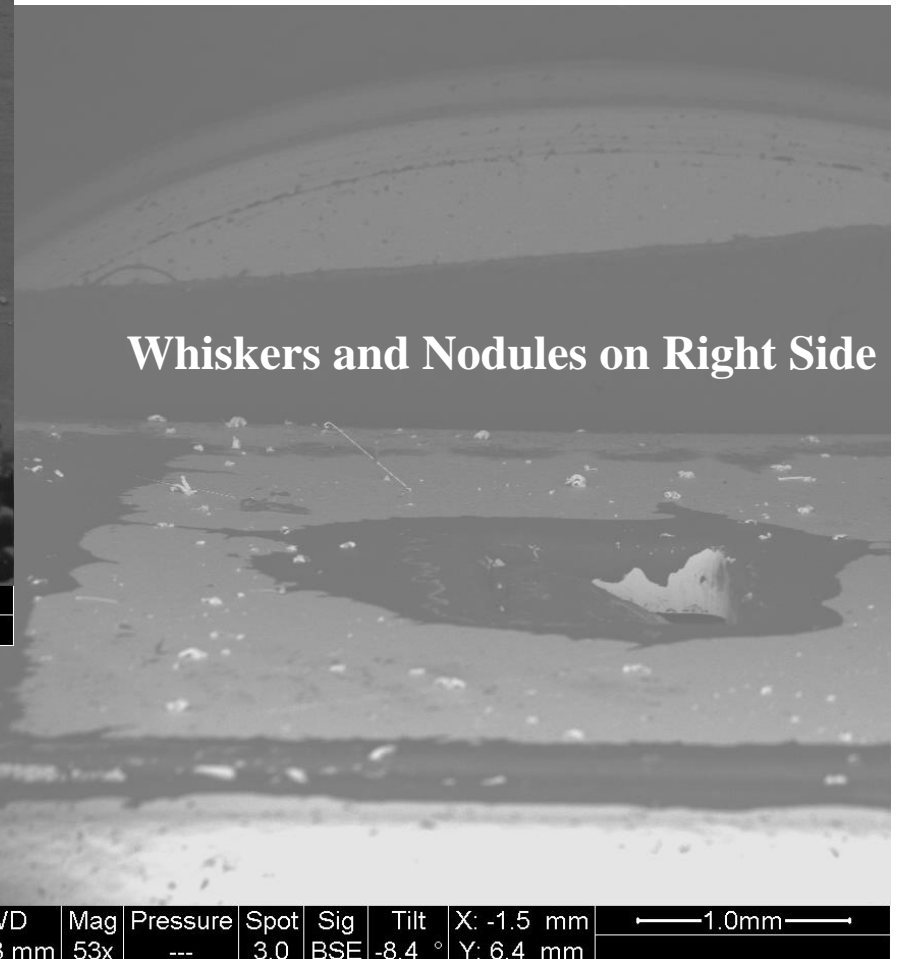
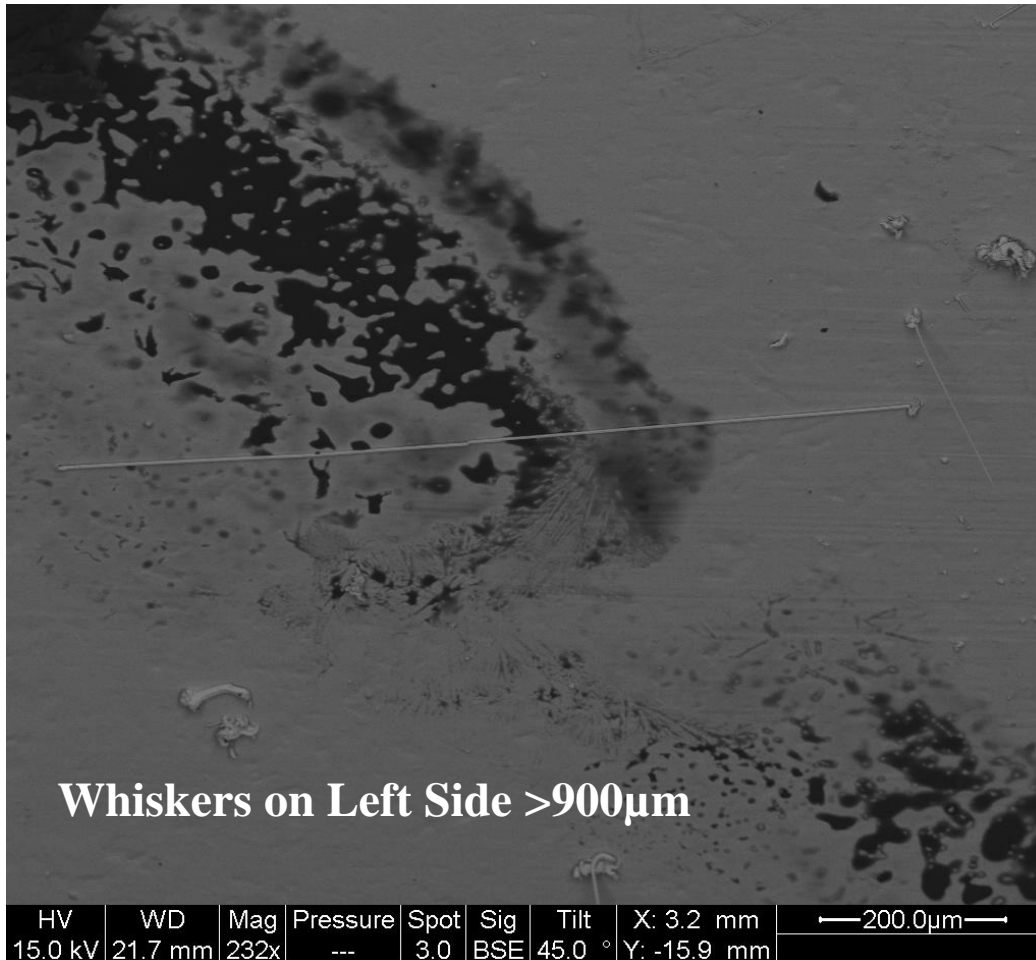


HV	WD	Mag	Pressure	Spot	Sig	Tilt	X: -2.0 mm	Y: 6.9 mm	100.0µm
15.0 kV	14.4 mm	631x	---	3.0	BSE	-8.4 °			

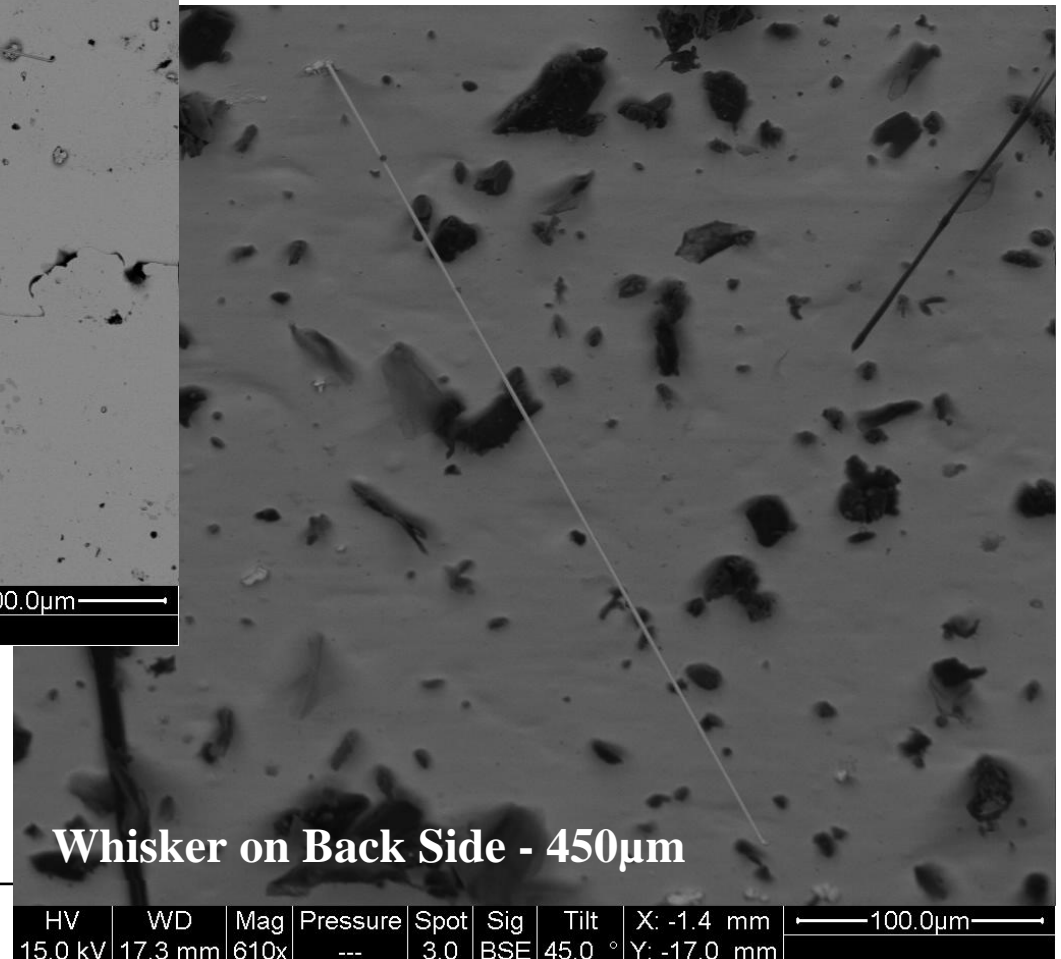
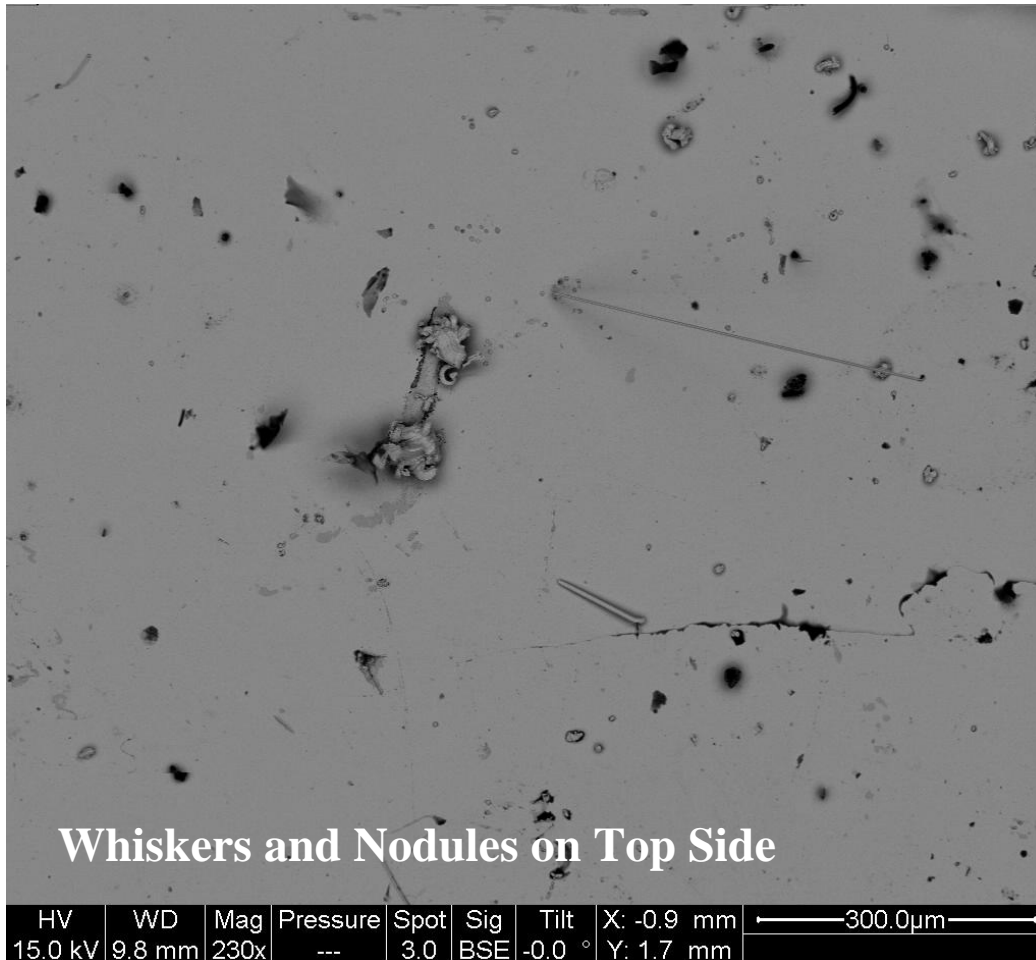
Whiskers and Nodules on Left Side

HV	WD	Mag	Pressure	Spot	Sig	Tilt	X: -2.0 mm	Y: 6.9 mm	1.0mm
15.0 kV	14.4 mm	58x	---	3.0	BSE	-8.4 °			

# Board 0337 – USB “B”



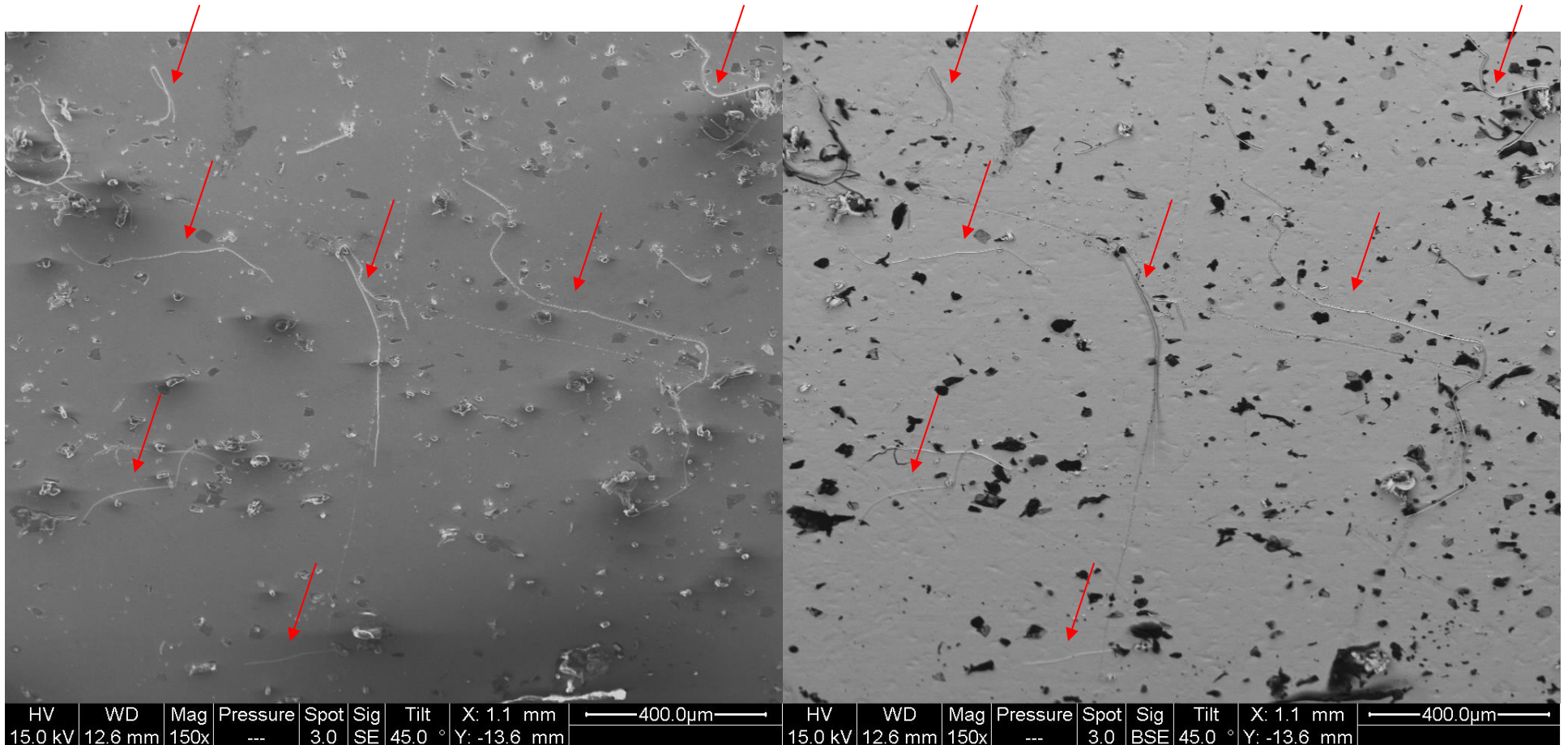
# Board 0337 – USB “B”



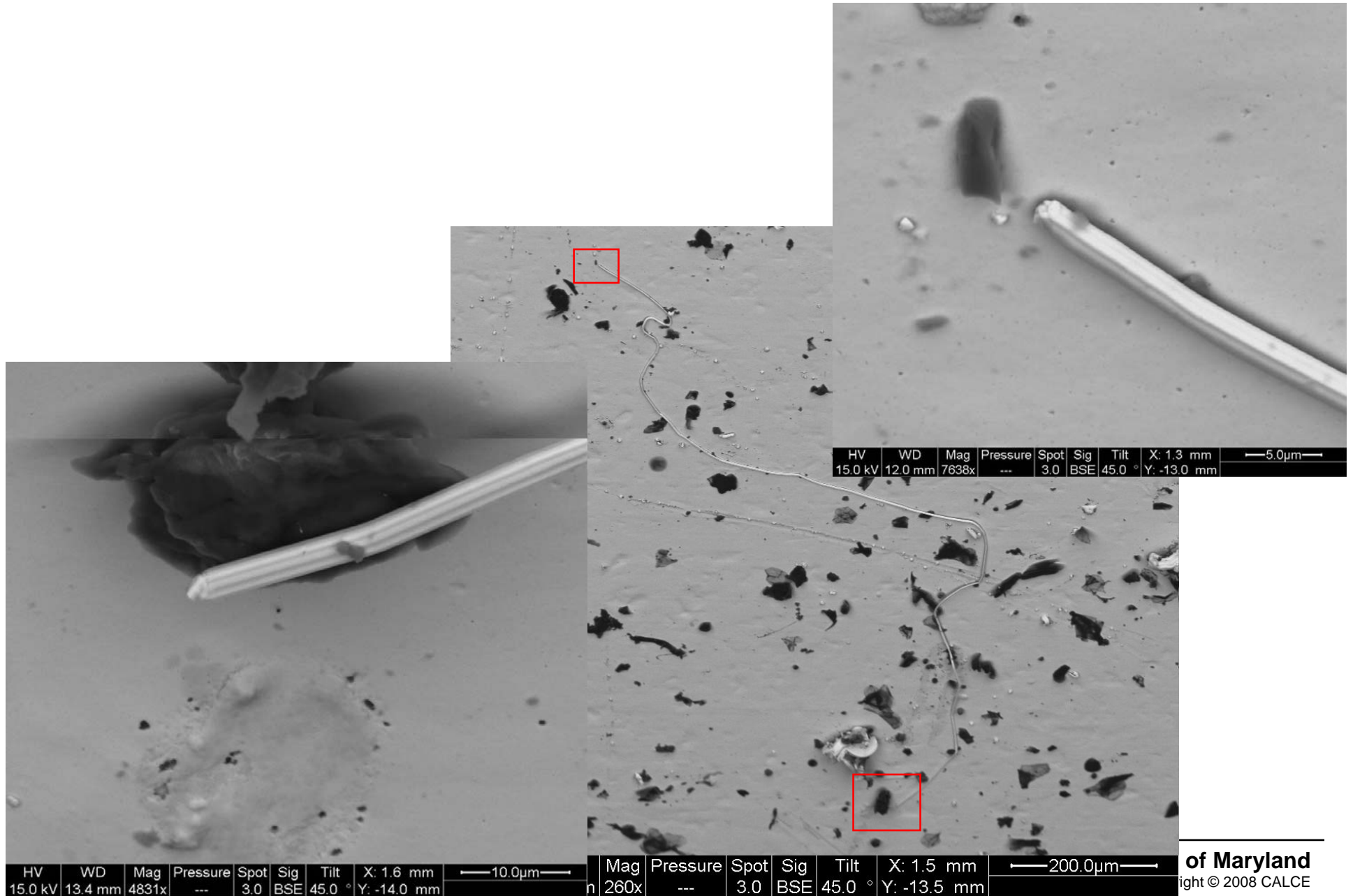


# Board 0337 – USB “B” Back Side

- Lots of debris, and a variety of long broken and bent whiskers



# Board 0337 – USB “B” Back Side



# Summary

- Failure of monitor boards traced to blown fuse.
- The cause of fuse failures is unknown.
- Tin whiskers were observed on USB housings.
- While tin whiskers may not be the source of failure in this case, their presence is a concern.



## Contact:

- For information on tin whiskers and assistance with tin whisker related issues, please contact
- Dr. Michael Osterman ([osterman@calce.umd.edu](mailto:osterman@calce.umd.edu))
- Investigation and images conducted by Research Associate Lyudmyla Panashchenko